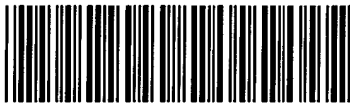


Search Notes



Application/Control No.

10/550,202

Examiner

Sang Y. Paik

Applicant(s)/Patent under
Reexamination

TANAKA ET AL.

Art Unit

3742

SEARCHED

Class	Subclass	Date	Examiner
392	416- 418		
219	402- 414,		
	483-		
	495		
118	724		
	725	1/31/07	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
5/15/07 SEARCHED	1/30/07	18